

3.0 μ m P-Well CMOS Process

Standard Features

- ❖ UTIX Stepper
- ❖ Single or double poly
- ❖ Single or double metal
- ❖ 5.5V max operating voltage

Process Technology

- ❖ EPI starting material provides latch-up protection

Process Options

- ❖ Low threshold for below 5V operation
(V_{in} and $V_{tp} = 0.5V$ or sum of $V_t < 1.2V$)
- ❖ High value poly resistor 1-2 or 25-60 k Ω /square
- ❖ Poly 2 (Cap Top Plate)
- ❖ Capacitor implant for poly to substrate cap
- ❖ 10V operation with modified layout and N-Ldd
- ❖ Low temperature coefficient SiCr resistor
(500 \pm 100 Ω K)
- ❖ P & E 760 aligner for large die

Standard Layout Rules and Process Parameters

	Value	Units
Min gate length (N&P)	3.0	μ m
Gate oxide	500	\AA
Inter-poly dielectric	700	\AA
Active (width/space)	4.0/3.0	μ m
Poly 1 (width/space)	3.0/3.0	μ m
Poly 2 (width/space)	3.0/3.0	μ m
Contact (width/space)	3.0/3.0	μ m
Via (width/space)	3.0/3.0	μ m
Metal 1 (width/space)	4.0/3.0	μ m
Metal 2 (width/space)	4.0/4.0	μ m

Process Option Parameters

- ❖ Low threshold process: V_{tn} and $V_{tp} = 0.5V$ or sum of $V_t < 1.2V$
- ❖ High value poly 2 resistor 1-2 or 25-60 k Ω /square
- ❖ N-Ldd N-ch for 10V operation,
(12V maximum) Min L=4 μ m (High voltage device has lower drive due to increase in SD resistance. Contact factory for details.)
- ❖ Low TC SiCr resistor: 500+/-100 Ω /square

Typical Electrical Parameters

	N-CH	P-CH	Units
$V_t(30X2.0\mu)$	0.95	-0.70	V
I_{ds}	0.07	-0.04	mA/ μ m
Gain μ C (30X30)	45	16	μ A/V ²
Body Effect	0.8	0.32	V ^{1/2}
Sub-threshold slope	100	100	mV/decade
L_{eff}	1.7	2.0	μ m
X_j	0.8	0.6	μ m
R_s	16	49	Ω /square
R_s poly1	11	—	Ω /square